A Concept for the Analysis of Cross Sensitivities in Modern RFID Systems



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Jue Wang

- Introduction
- Cross Sensitivities in RFID Transponder System
- On Chip Thermal Coupling
- Conclusion

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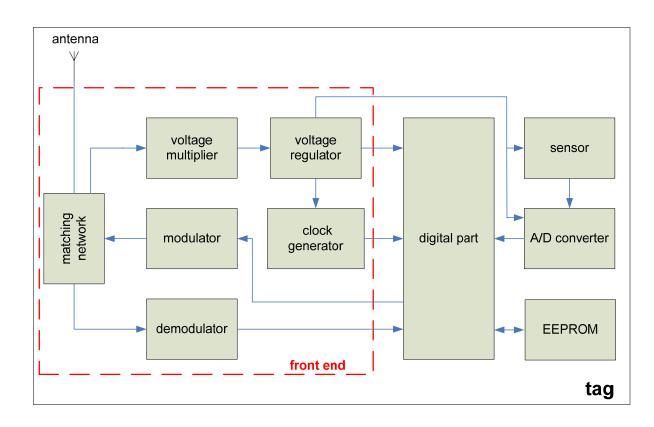
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Introduction

Architecture of a modern passive transponder system



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Cross Sensitivities

From the outside world

- Temperature Variation
- Mechanical Stress from Package
- Light Radiation
- Electrostatic Discharge (ESD)
- Chemical Materials

DIN EN ISO 9001:2000

Zertifikat: 09 100 5263

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Cross Sensitivities

From inside of the chip

- Crosstalk: capacitive coupling, substrate coupling
- Thermal Coupling
- Variation of Supply Voltage
- Latch-Up Effect
- Matching of sensitive components
- Leakage Current

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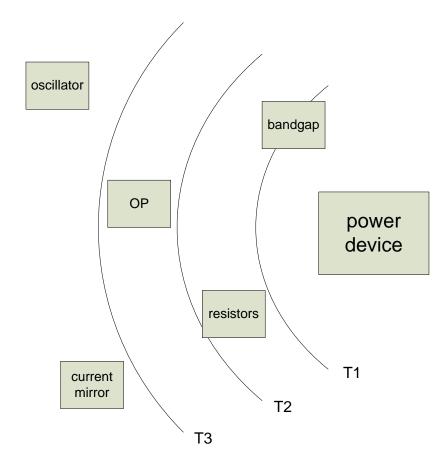
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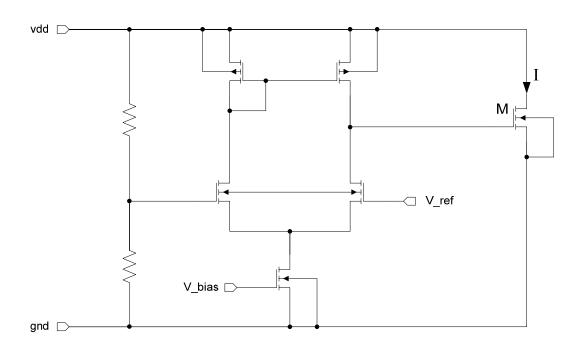
On chip temperature gradient:



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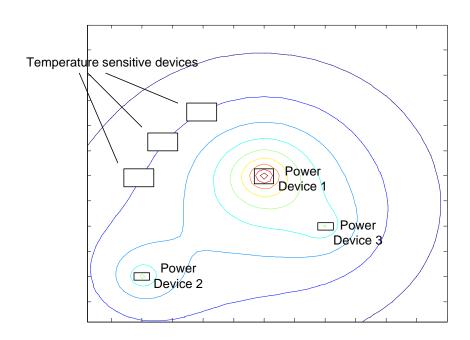
Heat source on chip: voltage protector



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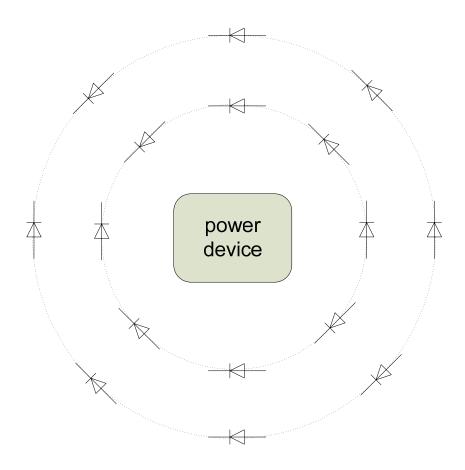
Temperature distribution with more than one heat source on chip



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Measurement of temperature gradient



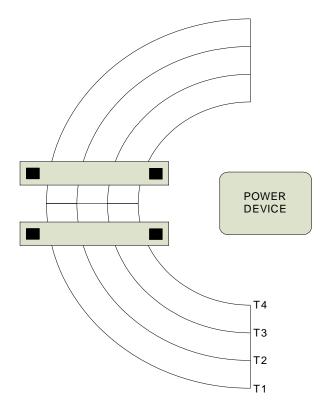
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Approaches to reduce the impact of thermal coupling:



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Conclusion

- Different types of cross sensitivities have been presented.
- Cross sensitivities can be a problem for modern transponder systems, as they are often overlooked during design process.
- System simulation in typical IC design flow does not consider problems such as temperature coupling.
- Approach to the matching, measurement and countermeasures against temperature coupling have been presented.

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Thank You!

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